

**Search Notes**

Application/Control No.

10/711,470

Examiner

Thien T. Mai

Applicant(s)/Patent under  
Reexamination

SHEI ET AL.

Art Unit

2876

**SEARCHED**

Class	Subclass	Date	Examiner
438	612	10/26/2005	TM
	613		
	106		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	10/26/2005	TM